



S/N 09/834,751

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Sergey A. Velichko et al.

Examiner: Manuel L. Barbee

Serial No.: 09/834,751

Group Art Unit: 2857

Filed: April 13, 2001

Docket No.: 303.750US1

Title: CONCURRENT CONTROL OF SEMICONDUCTOR PARAMETRIC  
TESTING

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AMENDMENT AND RESPONSE UNDER 37 CFR § 1.111

Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

This responds to the Office Action mailed on June 8, 2006. Applicants submit the following.